



## Exercise 2

2-1. Consider the circuit of Fig.2.1.

- Using the simple model with  $V_{Don} = 0.7V$ , solve for  $I_D$ ;
- Find  $I_D$  and  $V_D$  using the ideal diode equation. Use  $I_S = 10^{-14} A$  and  $T=300 K$ .

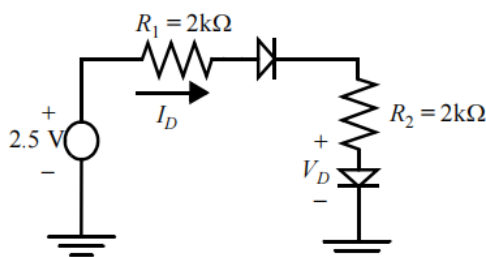


Fig.2.1

**Answer:**

$$a. \quad I_D = \frac{V_{in} - 2 \cdot V_{Don}}{R_1 + R_2} = \frac{2.5 - 2 \cdot 0.7}{4k\Omega} = 275 \mu A$$

$$b. \quad I_S = 10^{-14} A, T = 300 K, V_{Don} = 0.7 V. I_D = I_S \times (e^{\frac{V_D q}{KT}} - 1) \quad \text{where} \quad \frac{KT}{q} = 26 mV @ 300 K$$

$$I_D = \frac{V_{in} - 2 \cdot V_{Don}}{R_1 + R_2} = I_S \times (e^{\frac{V_D q}{KT}} - 1) \quad \text{iterating on this expression we can obtain} \quad \frac{V_D}{I_D} = \frac{0.628 V}{311 \mu A}$$

2-2. For the circuit in Fig.2.2,  $V_s = 3.3 V$ . Assume  $A_D = 12 \mu m^2$ ,  $\phi_0 = 0.65 V$ , and  $m = 0.5$ ,  $N_A = 2.5 \times 10^{16}$  and  $N_D = 5 \times 10^{15}$ .

- Is the diode forward- or reverse-biased?
- Find  $I_D$  and  $V_D$ ;
- Find the depletion region width,  $W_j$ , of the diode;
- Use the parallel-plate model to find the junction capacitance,  $C_j$ ;
- Set  $V_s = 1.5 V$ . Again using the parallel-plate model, explain qualitatively why  $C_j$  increases.

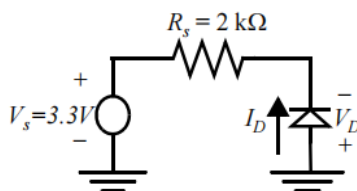


Fig.2.2

**Answer:**

- Reverse biased
- $I_D = I_{REV} = -I_S \approx 0, V_D = -V_s = -3.3 V$

$$c. \quad W_j = \sqrt{\frac{2 \cdot \epsilon_{si}}{q} \times \frac{N_A + N_D}{N_A N_D} \times (\phi_0 - V_D)}, q = 1.6 \times 10^{-19} C, V_D = -V_S = -3.3V,$$

$$\epsilon_{si} = 11.7\epsilon_0 = 1.035 \times 10^{-10} F/m, N_A = 2.5 \times \frac{10^{16}}{cm^3}, N_D = 5 \times \frac{10^{15}}{cm^3}.$$

$$W_j = 1.107 \times 10^{-4} cm.$$

$$d. \quad C_j = \frac{\epsilon_{si} \cdot A_D}{W_j}, A_D = 12 \times 10^{-8} cm^2, C_j = 1.12 \times 10^{-15} F.$$

e.  $V_{SNEW} = 1.5V < V_{SOLD} = 3.3V$ . The new voltage reduces the reverse bias of the PN junction, hence the width of the depletion region,  $W_j$ , decreases. As you bring the plates of capacitor together, the capacitance increases.

2-3. Fig.2.3 shows NMOS and PMOS devices with drains, source, and gate ports annotated. Determine the operation region (saturation, linear, or cut-off) and the drain current  $I_D$  for each of the biasing configurations given in table. Assume the model parameters from Table.2.1,  $V_{BS}=0$  and  $W/L = 1, L=1\mu m$ , fill the table

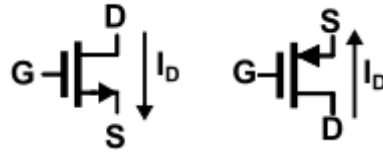


Fig.2.3

**Answer:**

	$V_{GS}(V)$	$V_{DS}(V)$	Operation region	$I_D$
NMOS	2.5	2.5	saturation	392.04uA
	3.3	2.2	linear	726uA
	0.6	0.1	cut-off	0
PMOS	-0.5	-1.25	cut-off	0
	-2.5	-1.8	saturation	176.58uA
	-2.5	-0.7	linear	101.5uA

NMOS :1. Saturation  $I_D = k'_n \frac{W}{L} (V_{GS} - V_{TH})^2 (1 + \lambda V_{DS}) = 392.04 \mu A;$

2. linear  $I_D = 2 \times k'_n \frac{W}{L} \left( (V_{GS} - V_{TH}) V_{DS} - \frac{V_{DS}^2}{2} \right) = 726 \mu A;$

3. cut-off  $I_D = 0,$

PMOS : 1. cut-off  $I_D = 0,$

2. Saturation  $I_D = k'_p \frac{W}{L} (V_{GS} - V_{TH})^2 (1 + \lambda V_{DS}) = 176.58 \mu A$

3. linear  $I_D = 2 \times k'_p \frac{W}{L} \left( (V_{GS} - V_{TH}) V_{DS} - \frac{V_{DS}^2}{2} \right) = 101.5 \mu A$

2-4. An NMOS device is plugged into the test configuration shown below in Fig .2.4 The input  $V_{in}$  is 2V. The current source draws a constant current of 50  $\mu$ A.  $R$  is a variable resistor between 10k $\Omega$  and 30 k $\Omega$ . Transistor M1 has following transistor parameters:  $k'_n = 110 \mu \text{ V/A}^2$ ,  $V_T = 0.7\text{V}$ , and  $V_{DSAT} = 0.6\text{V}$ , and has a  $W/L = 2.5\mu\text{m}/0.25\mu\text{m}$ . For simplicity, the body effect and channel length modulation can be neglected, i.e  $\lambda=0$ ,  $\gamma=0$ .

- a) When  $R=10\text{k}\Omega$  find the operation region,  $V_D$  and  $V_S$ .  
b) For the case of  $R = 10\text{k}\Omega$ , would  $V_S$  increase or decrease if  $\lambda \neq 0$ . Explain qualitatively.

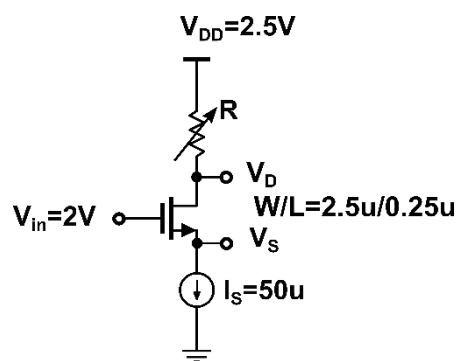


Fig.2.4

### Answer:

- a. When  $R = 10\text{K}$ ,  $V_D = V_{DD} - IR = 2.5 - 50 \times 10^{-6} \times 10^4 = 2.5 - 0.5 = 2\text{V}$ . Assume the device is in saturation  $I_D = k'_n \frac{W}{L} (V_{GS} - V_{TH})^2 = 50\mu\text{A}$  find  $V_{GS} - V_{TH} = 0.213\text{V}$ , so  $V_{GS} = 0.213 + 0.7\text{V} = 0.913\text{V}$ ,  
 $V_S = 1.087\text{V}$ .  $V_{GS} = 0.913\text{V}$ ,  $V_{DS} = 1.087\text{V}$  device in the saturation.  
b. Increase.  $V_D$  is fixed due to constant current.  $1 + \lambda V_{DS}$  term would try to increase the current more than 50uA, thus  $V_{GS}$  needs to reduce by increase  $V_S$ .

2-5. Find the small-signal model ( $g_m$ ,  $g_{mb}$ ,  $g_{ds}$ ) for an n-channel transistor with the drain at 4 V, gate at 4 V, source at 2 V, and the bulk at 0 V. Assume the model parameters from Table.2.1, and  $W/L = 10 \mu\text{m}/1 \mu\text{m}$ .

### Answer:

$$V_T = V_{T0} + \gamma \left[ \sqrt{2|\Phi_F| + v_{SB}} - \sqrt{2|\Phi_F|} \right]$$

$$V_T = 0.7 + 0.4 \left[ \sqrt{0.7 + 2.0} - \sqrt{0.7} \right] = 1.02$$

$$I_D = \frac{K'W}{L} (v_{GS} - v_T)^2 (1 + \lambda v_{DS})$$

$$I_D = 110 \times 10^{-6} \times 10 \times (2 - 1.02)^2 (1 + 0.04 \times 2) = 1140 \times 10^{-6}$$

$$g_m = \sqrt{4 \frac{K'W}{L} I_D}$$

$$g_m = \sqrt{4 \times 110 \times 10^{-6} \times 10 \times 1140 \times 10^{-6}} = 2.24 \times 10^{-3}$$

$$g_{mb} = g_m \frac{\gamma}{2(2|\Phi_F| + V_{SB})^{\frac{1}{2}}}$$

$$g_{mb} = 2.24 \times 10^{-3} \frac{0.4}{2(0.7 + 2.0)^{\frac{1}{2}}} = 273 \times 10^{-6}$$

$$g_{ds} = \frac{\lambda I_D}{1 + \lambda V_{DS}}$$

$$g_{ds} = 1140 \times 10^{-6} \times 0.04 \div 1.08 = 42.22 \times 10^{-6}$$

Thinking Questions(optional)

2-6. Show that two MOS transistors connected in parallel with channel widths of  $W_1$  and  $W_2$  and identical channel lengths of  $L$  can be modeled as one equivalent MOS transistor whose width is  $W_1 + W_2$  and whose length is  $L$ , as shown in Fig.2.6 Assume the transistors are identical except for their channel widths.

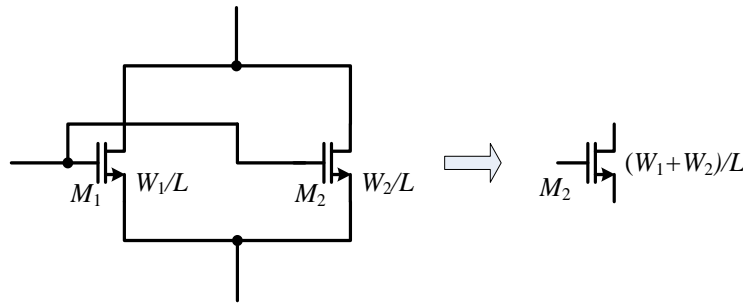


Fig.2.6

**Answer:**

For  $V_{DS} \leq V_{GS} - V_{TH}$

$$I_{D1} = \mu C_{OX} \frac{W_1}{L} [(V_{GS} - V_{TH})V_{DS} - \frac{1}{2}V_{DS}^2]$$

$$I_{D2} = \mu C_{OX} \frac{W_2}{L} [(V_{GS} - V_{TH})V_{DS} - \frac{1}{2}V_{DS}^2]$$

.....

$$I_{Dn} = \mu C_{OX} \frac{W_n}{L} [(V_{GS} - V_{TH})V_{DS} - \frac{1}{2}V_{DS}^2]$$

$$\therefore I_D = I_{D1} + I_{D2} + \dots + I_{Dn} = \mu C_{OX} \frac{W_1 + W_2 + \dots + W_n}{L} [(V_{GS} - V_{TH})V_{DS} - \frac{1}{2}V_{DS}^2]$$

For  $V_{DS} \geq V_{GS} - V_{TH}$

$$I_D = I_{D1} + I_{D2} + \dots + I_{Dn} = \frac{1}{2} \mu C_{OX} \frac{W_1 + W_2 + \dots + W_n}{L} (V_{GS} - V_{TH})^2$$

Thus the equivalent length = L and the equivalent width =  $W_1 + W_2 + \dots + W_n$ .

2-7. Show that two MOS transistors connected in series with channel lengths of  $L_1$  and  $L_2$  and identical channel widths of  $W$  can be modeled as one equivalent MOS transistor whose width is  $W$  and whose length is  $L_1+L_2$ , as shown in Fig. 2.7. Assume the transistors are identical except for their channel lengths. Ignore the body effect and channel-length modulation.

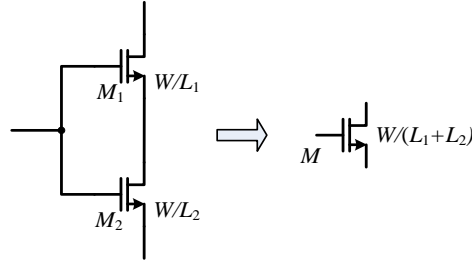
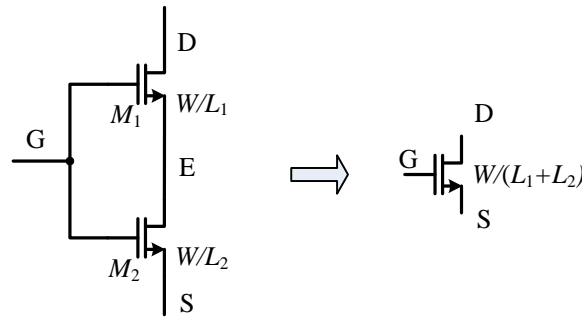


Fig.2.7

**Answer:**



- (1) When  $V_{GS} < V_{TH}$  and  $V_{GE} < V_{GS} < V_{TH}$ , the MOSFETs are in cut off.
- (2) While M1 operates in triode ( $V_{DE} < V_{GE} - V_{THN}$ ), that is equivalent to  $V_{DE} + V_{ES} < V_{GE} + V_{ES} - V_{THN}$ , i.e.  $V_{DS} < V_{GS} - V_{THN}$ .  
Thus M2 operates in triode, too.

Thus

$$I_{D1} = \mu_n C_{OX} \frac{W}{L_1} [(V_{GE} - V_{TH})V_{DE} - \frac{1}{2}V_{DE}^2] \quad (1)$$

$$I_{D2} = \mu_n C_{OX} \frac{W}{L_2} [(V_{GS} - V_{TH})V_{ES} - \frac{1}{2}V_{ES}^2] \quad (2)$$

Since

$$V_{DS} = V_{DE} + V_{ES} \quad (3)$$

$$V_{GE} = V_{GS} - V_{ES} \quad (4)$$

$$I_{D1} = I_{D2} = I_D \quad (5)$$

It can be derived from equations (1), (2), (3), (4) and (5) that

$$\begin{aligned}
(V_{GS} - V_{TH})V_{ES} - \frac{1}{2}V_{ES}^2 &= \frac{L_2}{L_1}[(V_{GS} - V_{TH} - V_{ES})(V_{DS} - V_{ES}) - \frac{1}{2}(V_{DS} - V_{ES})^2] \\
&= \frac{L_1}{L_1 + L_2}[(V_{GS} - V_{TH})V_{DS} - \frac{1}{2}V_{DS}^2]
\end{aligned}$$

So we can get  $I_D = \mu_n C_{OX} \frac{W}{L_1 + L_2} [(V_{GS} - V_{TH})V_{DS} - \frac{1}{2}V_{DS}^2]$

(3) While M1 operates in saturation ( $V_{DE} > V_{GE} - V_{THN}$ ). It means  $V_{DE} + V_{ES} > V_{GE} + V_{ES} - V_{THN}$ , i.e.  $V_{DS} > V_{GS} - V_{THN}$ .

$V_E = V_G - V_{GE} < V_G - V_{THN}$ , it means  $V_{ES} < V_{GS} - V_{THN}$ . M2 operates in triode.

So

$$I_{D1} = \frac{1}{2} \mu_n C_{OX} \frac{W}{L_1} (V_{GE} - V_{TH})^2 \quad (1)$$

$$I_{D2} = \frac{1}{2} \mu_n C_{OX} \frac{W}{L_2} [2(V_{GS} - V_{TH})V_{ES} - V_{ES}^2] \quad (2)$$

$$V_{DS} = V_{DE} + V_{ES} \quad (3)$$

$$V_{GE} = V_{GS} - V_{ES} \quad (4)$$

$$I_{D1} = I_{D2} = I_D \quad (5)$$

It can be derived from equations (1), (2), (3), (4) and (5) that

$$I_D = \frac{1}{2} \mu_n C_{OX} \frac{W}{L_1 + L_2} (V_{GS} - V_{TH})^2$$

That just like a MOSFET operating in saturation, which has a length of  $L_1 + L_2$  and a width of  $W$ . It can be deducted similarly that  $n$  MOSFETs in series acts as a MOSFET with an aspect ratio of  $W/(L_1 + L_2 + \dots L_n)$ .

Table.2.1

Parameter Symbol	Parameter Description	Typical Parameter Value		Units
		n-Channel	p-Channel	
$V_{T0}$	Threshold voltage ( $V_{BS}=0$ )	0.7	-0.7	V
$K'$	Transconductance parameter ( in saturation)	110.0	50.0	$\mu\text{A}/\text{V}^2$
$\gamma$	Bulk threshold parameter	0.4	0.57	$\text{V}^{1/2}$
$\lambda$	Channel length modulation parameter	0.04 (L=1 $\mu\text{m}$ ) 0.01 (L=2 $\mu\text{m}$ )	0.05 (L=1 $\mu\text{m}$ ) 0.01 (L=2 $\mu\text{m}$ )	$\text{V}^{-1}$
$2 \Phi_F $	Surface potential at strong inversion	0.7	0.8	V

$$*K' = \frac{1}{2} \mu C_{ox}$$